

Notice of References Cited	Application/Control No. 10/529,533		Applicant(s)/Patent Under Reexamination FAYET ET AL.	
	Examiner Keath T. Chen		Art Unit 1762	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,339,584	08-1994	Ohtake et al.	52/208
*	B	US-5,322,605	06-1994	Yamanishi, Hitoshi	204/298.07
*	C	US-4,738,761	04-1988	Bobbio et al.	204/192.12
*	D	US-6,306,265	10-2001	Fu et al.	204/192.12
*	E	US-6,168,698	01-2001	Szczyrbowski et al.	204/298.25
*	F	US-2002/0158616	10-2002	Kovalevski et al.	323/331
*	G	US-2001/0010207	08-2001	Yamamoto et al.	118/723.0MW
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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